

DEELS 2023

Monday 19 June 2023

Session 2: Profile and Emittance Diagnostics ----- Location: Seminar Room1, Bldg. 1 (16:00 - 17:30)

time	[id] title	presenter
16:00	[49] Radiation damage around ESRF X-ray pinholes	EWALD, Friederike
16:30	[50] Transverse emittance measurements at PITZ	RICHARD, Christopher James
17:00	[51] Bunch length monitoring using a spectrum analyzer	BAÑUELOS SÁNCHEZ, Javier